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PATENT  
Attorney Docket No. 11856.00

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re the Application of:

Roman Sobolewski et al.

Appln. No. 09/628,116

Filed: July 28, 2000

For: SUPERCONDUCTING SINGLE PHOTON  
DETECTOR

Confirmation No.: 2593

Group Art Unit: 2878

Examiner: Timothy J. Moran

**COMBINED POWER OF ATTORNEY BY ASSIGNEE  
AND SUBMISSION UNDER 37 C.F.R. §§ 3.71 AND 3.73(b)**

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Sir:

As an officer of NPTest, LLC. ("assignee"), a Delaware corporation, I hereby certify that the undersigned is a representative authorized and empowered to sign on behalf of the assignee, and that to the best of assignee's knowledge and belief it is the assignee of the entire right, title and interest in and to the above-referenced patent application by virtue of either:

- A. ☐ An assignment from the inventor(s) of the patent application identified above,  
☐ 1. a copy of which is attached; or  
☐ 2. which is recorded in the U.S. Patent and Trademark Office at Reel \_\_\_\_\_, Frame \_\_\_\_\_, a copy of which is attached.

OR

- B. ☒ A chain of title from the inventor(s), of the patent application identified above, to the current assignee as shown below:

1. From: Kenneth R Wilsher and Steven A. Kasapi  
To: Schlumberger Technologies, Inc.  
The document was recorded in the U.S. Patent and Trademark Office at Reel 011477 Frame 0700, a copy of which is attached.

2. From: Schlumberger Technologies, Inc.  
To: NPTest, LLC

The document was recorded in the U.S. Patent and Trademark Office at Reel  
014268 Frame 0115, or a copy of which is attached.

Assignee hereby appoints on its behalf the following patent attorneys to prosecute the  
patent application identified above and to transact all business in the Patent Office connected  
therewith:

Dorsey & Whitney LLP  
USPTO Customer No. 20686

Pursuant to 37 C.F.R. § 3.71, the assignee hereby states that prosecution of the above-  
referenced patent application is to be conducted to the exclusion of the inventors.

Send all correspondence relating to this matter to:

Dorsey & Whitney LLP  
USPTO Customer No. 20686

Direct all telephone calls to **Gregory P. Durbin** at **(303) 629-3427**.

The undersigned hereby declares that all statements made herein of his/her own  
knowledge are true and that all statements made on information and belief are believed to be  
true; and further that these statements were made with the knowledge that willful false  
statements and the like so made are punishable by fine or imprisonment, or both, under  
Title 18, United States Code, § 1001 and that such willful false statements may jeopardize the  
validity of the application or any patent issuing thereon.

Signed this 16<sup>th</sup> day of April, 2004.

ASSIGNEE:

NPTest, LLC.

By Julie Weise  
Name: Leslie Weise  
Title: General Counsel  
Address: 150 Baytech Drive  
San Jose, California 95134



UNITED STATES DEPARTMENT OF COMMERCE  
Patent and Trademark Office

ASSISTANT SECRETARY AND COMMISSIONER  
OF PATENTS AND TRADEMARKS  
Washington, D.C. 20231

APRIL 13, 2001

SKJERVEN MORRILL MACPHERSON LLP  
NORMAN R. KLIVANS  
25 METRO DRIVE  
SUITE 700  
SAN JOSE, CA 95110

PTAS RECEIVED  
BY DOCKET DEPT.



\*101603893A\*

APR 20 2001

SKJERVEN, MORRILL, MACPHERSON,  
LLP.

UNITED STATES PATENT AND TRADEMARK OFFICE  
NOTICE OF RECORDATION OF ASSIGNMENT DOCUMENT

THE ENCLOSED DOCUMENT HAS BEEN RECORDED BY THE ASSIGNMENT DIVISION OF THE U.S. PATENT AND TRADEMARK OFFICE. A COMPLETE MICROFILM COPY IS AVAILABLE AT THE ASSIGNMENT SEARCH ROOM ON THE REEL AND FRAME NUMBER REFERENCED BELOW.

PLEASE REVIEW ALL INFORMATION CONTAINED ON THIS NOTICE. THE INFORMATION CONTAINED ON THIS RECORDATION NOTICE REFLECTS THE DATA PRESENT IN THE PATENT AND TRADEMARK ASSIGNMENT SYSTEM. IF YOU SHOULD FIND ANY ERRORS OR HAVE QUESTIONS CONCERNING THIS NOTICE, YOU MAY CONTACT THE EMPLOYEE WHOSE NAME APPEARS ON THIS NOTICE AT 703-308-9723. PLEASE SEND REQUEST FOR CORRECTION TO: U.S. PATENT AND TRADEMARK OFFICE, ASSIGNMENT DIVISION, BOX ASSIGNMENTS, CG-4, 1213 JEFFERSON DAVIS HWY, SUITE 320, WASHINGTON, D.C. 20231.

RECORDATION DATE: 01/23/2001

REEL/FRAME: 011477/0700  
NUMBER OF PAGES: 3

BRIEF: ASSIGNMENT OF ASSIGNOR'S INTEREST (SEE DOCUMENT FOR DETAILS).

ASSIGNOR:  
WILSHER, KENNETH R.

DOC DATE: 12/04/2000

ASSIGNOR:  
KASAPI, STEVEN A.

DOC DATE: 12/13/2000





ASSIGNEE:  
SCHLUMBERGER TECHNOLOGIES, INC.  
150 BAYTECH DRIVE  
SAN JOSE, CALIFORNIA 95134

SERIAL NUMBER: 09628116  
PATENT NUMBER:

FILING DATE: 07/28/2000  
ISSUE DATE:

SHARON LATIMER, EXAMINER  
ASSIGNMENT DIVISION  
OFFICE OF PUBLIC RECORDS

ATTORNEY: NRK  
ACTION: Petition DUE: 4-5-01  
ACTION: File Due DUE: 7-25-01  
ACTION: Status DUE: 1-28-02  
F DOCKETED BY: TE DATE: 4-25-01  
FORM LETTER: YES/NO

<div style="display: flex; justify-content: space-between; align-items: center;"> <div style="text-align: left;"> <p>1.23.01</p> <p>APR 19 2004</p> </div> <div style="text-align: center;"> <p>02-05-2001</p>  <p>101603893</p> </div> <div style="text-align: right;"> <p>U.S. DEPARTMENT OF COMMERCE</p> <p>Patent and Trademark Office</p> </div> </div>				
<p>To the Honorable Director of <del>Patent</del> and Trademarks. Please record the attached original documents or copy thereof.</p>				
<p>1. Name of conveying parties:</p> <p>Kenneth R. Wilsher (1) and Steven A. Kasapi (2)</p> <p>Additional names of conveying party attached?</p> <p style="text-align: right;"><input type="checkbox"/> Yes <input checked="" type="checkbox"/> No</p>	<p>2. Name and address of receiving party:</p> <p>Name: <u>Schlumberger Technologies, Inc.</u></p> <p>Street Address: <u>150 Baytech Drive</u></p> <p>City: <u>San Jose</u> State: <u>CA</u> Zip: <u>95134</u></p> <p>Country: <u>USA</u></p>			
<p>3. Nature of Conveyance:</p> <p><input checked="" type="checkbox"/> Assignment <input type="checkbox"/> Merger</p> <p><input type="checkbox"/> Security Agreement <input type="checkbox"/> Change of Name</p> <p><input type="checkbox"/> Other _____</p> <p>Execution Date: <u>(1) 12/04/00 and (2) 12/13/00</u></p>				
<p>4. Application number(s) or patent number(s):</p> <p>If this document is being filed together with a new application, the execution date of the application is: _____</p> <table style="width: 100%;"> <tr> <td style="width: 50%;"> <p>A. Patent Application No.(s) -</p> <p>09/628,116 filed Jul 27, 2000 entitled "Superconducting Single Photon Detector"</p> </td> <td style="width: 50%;"> <p>B. Patent No.(s)</p> </td> </tr> </table> <p style="text-align: right;">Additional numbers attached? <input type="checkbox"/> Yes <input checked="" type="checkbox"/> No</p>		<p>A. Patent Application No.(s) -</p> <p>09/628,116 filed Jul 27, 2000 entitled "Superconducting Single Photon Detector"</p>	<p>B. Patent No.(s)</p>	
<p>A. Patent Application No.(s) -</p> <p>09/628,116 filed Jul 27, 2000 entitled "Superconducting Single Photon Detector"</p>	<p>B. Patent No.(s)</p>			
<p>5. Name and address of party to whom correspondence concerning document should be mailed:</p> <p>Name: <u>Norman R. Klivans</u></p> <p>Internal Address: <u>SKJERVEN MORRILL MacPHERSON LLP</u></p> <p>Street Address: <u>25 METRO DRIVE, SUITE 700</u></p> <p>City <u>SAN JOSE</u> State <u>CA</u> ZIP <u>95110</u></p>	<p>6. Total number of applications and patents involved: <u>ONE</u></p>			
	<p>7. Total fee (37 CFR 3.41): ..... <u>\$40.00</u></p> <p><input checked="" type="checkbox"/> Authorized to be charged to Deposit Account 19-2386</p> <p><input checked="" type="checkbox"/> Charge Deposit Account 19-2386 for any additional fees required for this conveyance and credit deposit account 19-2386 any amounts overpaid</p>			
<p>02/02/2001 DBYRNE 00000122 192386 09628116</p> <p>01 EC:581 40.00 CH</p> <p>DO NOT USE THIS SPACE</p>				
<p>8. Statement and signature.</p> <p><i>To the best of my knowledge and belief, the foregoing information is true and correct and any attached copy is a true copy of the original document.</i></p> <table style="width: 100%;"> <tr> <td style="width: 30%;"> <p><u>Norman R. Klivans</u> <u>33,003</u></p> <p>Name of Person Signing</p> </td> <td style="width: 40%; text-align: center;"> <p></p> <p>Signature</p> </td> <td style="width: 30%; text-align: right;"> <p><u>1/19/01</u></p> <p>Date</p> </td> </tr> </table> <p style="text-align: right;">Total number of pages comprising cover sheet: <u>THREE</u></p>		<p><u>Norman R. Klivans</u> <u>33,003</u></p> <p>Name of Person Signing</p>	<p></p> <p>Signature</p>	<p><u>1/19/01</u></p> <p>Date</p>
<p><u>Norman R. Klivans</u> <u>33,003</u></p> <p>Name of Person Signing</p>	<p></p> <p>Signature</p>	<p><u>1/19/01</u></p> <p>Date</p>		

# ASSIGNMENT

For good and valuable consideration, receipt of which is hereby acknowledged we,

Kenneth R. Wilsher

Of Palo Alto, California

Steven A. Kasapi

Of San Francisco, California

hereby sell, assign and transfer to Schlumberger Technologies, a Delaware corporation, having a place of business at 150 Baytech Drive, San Jose, CA 95134, its successors and assigns, the entire right, title and interest throughout the world in our invention in:

## Superconducting Single Photon Detector

for which we have executed a United States patent application on July 27, 2000, and now has Application Serial No. 09/628,116, and all patent applications and patents of every country for said invention, including divisions, reissues, continuations and extensions thereof, and all rights of priority resulting from the filing of said applications; we authorize the above-named assignee to apply for patents of foreign countries for said invention, and to claim all rights of priority without further authorization from us; we agree to execute all papers useful in connection with said United States and foreign applications, and generally to do everything possible to aid said assignee, their successors, assigns and nominees, at their request and expense, in obtaining and enforcing patents for said invention in all countries; and we request the Commissioner of Patents and Trademarks to issue all patents granted for said invention to the above-named assignee, its successors and assigns.

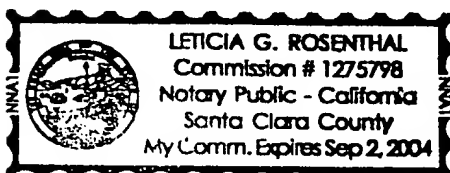
Executed this 4<sup>th</sup> day of December, 2000.

Kenneth R. Wilsher  
Kenneth R. Wilsher

State of California )  
 ) ss.  
County of Santa Clara

On December 4<sup>th</sup>, 2000 before me, Leticia G. Rosenthal  
personally appeared Kenneth R. Wilsher personally known to  
me or proved to me on the basis of satisfactory evidence to be the person(s) whose name(s)  
is(are) subscribed to the within instrument and acknowledged to me that he/she/they executed the  
same in his/her/their authorized capacity(ies), and that by his/her/their signature(s) on the  
instrument the person(s), or the entity upon behalf of which the person(s) acted, executed the  
instrument.

WITNESS my hand and official seal.



Leticia G. Rosenthal  
SIGNATURE OF NOTARY

Executed this 13 day of December, 2000.

Steven A. Kasapi  
Steven A. Kasapi

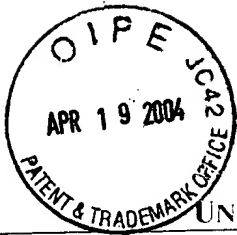
State of California )  
County of Santa Clara ) ss.

On December 13, 2000 before me, Leticia G. Rosenthal,  
personally appeared Steven A. Kasapi personally known to  
me or proved to me on the basis of satisfactory evidence to be the person(s) whose name(s)  
is(are) subscribed to the within instrument and acknowledged to me that he/~~she~~/~~they~~ executed the  
same in his/~~her~~/~~their~~ authorized capacity(ies), and that by his/~~her~~/~~their~~ signature(s) on the  
instrument the person(s), or the entity upon behalf of which the person(s) acted, executed the  
instrument.

WITNESS my hand and official seal.



Leticia G. Rosenthal  
SIGNATURE OF NOTARY



UNITED STATES PATENT AND TRADEMARK OFFICE

UNDER SECRETARY OF COMMERCE FOR INTELLECTUAL PROPERTY AND  
DIRECTOR OF THE UNITED STATES PATENT AND TRADEMARK OFFICE

JANUARY 21, 2004

PTAS



\*102484586A\*

SKADDEN, ARPS, SLATE, MEAGHER  
& FLOM, LLP  
FREDERICK D. KIM  
525 UNIVERSITY AVENUE, SUITE 1100  
PALO ALTO, CA 94301

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RECORDATION DATE: 06/23/2003

REEL/FRAME: 014268/0115  
NUMBER OF PAGES: 28

BRIEF: ASSIGNMENT OF ASSIGNOR'S INTEREST (SEE DOCUMENT FOR DETAILS).

ASSIGNOR:  
SCHLUMBERGER TECHNOLOGIES, INC.

DOC DATE: 05/10/2002

ASSIGNEE:  
NPTEST, LLC  
150 BAYTECH DRIVE  
SAN JOSE, CALIFORNIA 95134

SERIAL NUMBER: 09350611  
PATENT NUMBER:

FILING DATE: 07/09/1999  
ISSUE DATE:

SERIAL NUMBER: 09410569  
PATENT NUMBER:

FILING DATE: 10/01/1999  
ISSUE DATE:

SERIAL NUMBER: 09419317  
PATENT NUMBER: 6661836

FILING DATE: 10/17/1999  
ISSUE DATE: 12/09/2003



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SERIAL NUMBER: 09421784  
PATENT NUMBER: 6671845

FILING DATE: 10/19/1999  
ISSUE DATE: 12/30/2003

SERIAL NUMBER: 09628116  
PATENT NUMBER:

FILING DATE: 07/28/2000  
ISSUE DATE:

SERIAL NUMBER: 09648716  
PATENT NUMBER: 6622107

FILING DATE: 08/25/2000  
ISSUE DATE: 09/16/2003

SERIAL NUMBER: 09676292  
PATENT NUMBER:

FILING DATE: 09/28/2000  
ISSUE DATE:

SERIAL NUMBER: 09675981  
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FILING DATE: 09/29/2000  
ISSUE DATE: 10/07/2003

SERIAL NUMBER: 09679042  
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FILING DATE: 03/19/2002  
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FILING DATE: 03/25/2002  
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FILING DATE: 04/23/2003  
ISSUE DATE:

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FILING DATE: 04/30/2002  
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SERIAL NUMBER: 06472427  
PATENT NUMBER: 4594544

FILING DATE: 03/07/1983  
ISSUE DATE: 06/10/1986

SERIAL NUMBER: 06611454  
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FILING DATE: 05/17/1984  
ISSUE DATE: 11/18/1986

SERIAL NUMBER: 06611266  
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ISSUE DATE: 03/17/1987

SERIAL NUMBER: 06631958  
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FILING DATE: 07/18/1984  
ISSUE DATE: 06/16/1987

SERIAL NUMBER: 06798592  
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FILING DATE: 11/15/1985  
ISSUE DATE: 11/10/1987

SERIAL NUMBER: 06828157  
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FILING DATE: 02/10/1986  
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SERIAL NUMBER: 06932762  
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FILING DATE: 11/19/1986  
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FILING DATE: 08/16/1985  
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FILING DATE: 12/12/1988  
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FILING DATE: 05/17/1988  
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SERIAL NUMBER: 07276359  
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ISSUE DATE: 02/25/1992

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FILING DATE: 07/17/1991  
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ISSUE DATE: 08/18/1992

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FILING DATE: 07/25/1991  
ISSUE DATE: 09/01/1992

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SERIAL NUMBER: 07710768  
PATENT NUMBER: 5210487

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SERIAL NUMBER: 07577986  
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ISSUE DATE: 11/24/1998

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ISSUE DATE: 03/16/1999

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ISSUE DATE: 05/18/1999

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ISSUE DATE: 05/18/1999

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ISSUE DATE: 06/15/1999

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PATENT NUMBER: 5920073

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ISSUE DATE: 07/06/1999

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PATENT NUMBER: 5944846

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ISSUE DATE: 08/31/1999

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PATENT NUMBER: 5959458

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ISSUE DATE: 09/28/1999

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ISSUE DATE: 11/30/1999

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PATENT NUMBER: 6006346

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ISSUE DATE: 12/21/1999

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PATENT NUMBER: 6014764

FILING DATE: 05/20/1997  
ISSUE DATE: 01/11/2000

SERIAL NUMBER: 09082455  
PATENT NUMBER: 6031229

FILING DATE: 05/20/1998  
ISSUE DATE: 02/29/2000

SERIAL NUMBER: 08930492  
PATENT NUMBER: 6049900

FILING DATE: 09/30/1997  
ISSUE DATE: 04/11/2000

SERIAL NUMBER: 08762611  
PATENT NUMBER: 6061815

FILING DATE: 12/09/1996  
ISSUE DATE: 05/09/2000

SERIAL NUMBER: 08756296  
PATENT NUMBER: 6078845

FILING DATE: 11/25/1996  
ISSUE DATE: 06/20/2000

SERIAL NUMBER: 08949747  
PATENT NUMBER: 6081484

FILING DATE: 10/14/1997  
ISSUE DATE: 06/27/2000

SERIAL NUMBER: 08977649  
PATENT NUMBER: 6128754

FILING DATE: 11/24/1997  
ISSUE DATE: 10/03/2000

SERIAL NUMBER: 09367376  
PATENT NUMBER: 6181117

FILING DATE: 10/25/1999  
ISSUE DATE: 01/30/2001

SERIAL NUMBER: 09163710  
PATENT NUMBER: 6225626

FILING DATE: 09/30/1998  
ISSUE DATE: 05/01/2001

SERIAL NUMBER: 09483463  
PATENT NUMBER: 6252222

FILING DATE: 01/13/2000  
ISSUE DATE: 06/26/2001

SERIAL NUMBER: 09284939  
PATENT NUMBER: 6263464

FILING DATE: 04/22/1999  
ISSUE DATE: 07/17/2001

SERIAL NUMBER: 09452058  
PATENT NUMBER: 6285963

FILING DATE: 11/30/1999  
ISSUE DATE: 09/04/2001

SERIAL NUMBER: 09440985  
PATENT NUMBER: 6410924

FILING DATE: 11/16/1999  
ISSUE DATE: 06/25/2002

SERIAL NUMBER: 09676144  
PATENT NUMBER: 6420888

FILING DATE: 09/29/2000  
ISSUE DATE: 07/16/2002

014268/0115 PAGE 7

SERIAL NUMBER: 09526979  
PATENT NUMBER: 6462814

FILING DATE: 03/15/2000  
ISSUE DATE: 10/08/2002

SERIAL NUMBER: 09514708  
PATENT NUMBER: 6492797

FILING DATE: 02/28/2000  
ISSUE DATE: 12/10/2002

SERIAL NUMBER: 09500757  
PATENT NUMBER: 6496261

FILING DATE: 02/08/2000  
ISSUE DATE: 12/17/2002

SERIAL NUMBER: 09526407  
PATENT NUMBER: 6496953

FILING DATE: 03/15/2000  
ISSUE DATE: 12/17/2002

SERIAL NUMBER: 09643576  
PATENT NUMBER: 6501706

FILING DATE: 08/22/2000  
ISSUE DATE: 12/31/2002

SERIAL NUMBER: 09675090  
PATENT NUMBER: 6501288

FILING DATE: 09/28/2000  
ISSUE DATE: 12/31/2002

SERIAL NUMBER: 09871541  
PATENT NUMBER: 6514866

FILING DATE: 05/31/2001  
ISSUE DATE: 02/04/2003

SERIAL NUMBER: 09781488  
PATENT NUMBER: 6518571

FILING DATE: 02/10/2001  
ISSUE DATE: 02/11/2003

SERIAL NUMBER: 10132051  
PATENT NUMBER: 6522162

FILING DATE: 04/24/2002  
ISSUE DATE: 02/18/2003

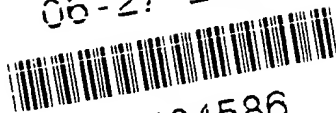
SERIAL NUMBER: 09510101  
PATENT NUMBER: 6553522

FILING DATE: 02/22/2000  
ISSUE DATE: 04/22/2003

MAURICE CARTER, PARALEGAL  
ASSIGNMENT DIVISION  
OFFICE OF PUBLIC RECORDS



06-27-2003



102484586

U.S. Department of Commerce  
Patent and Trademark Office

To the Honorable Commissioner of Patents and Trademarks: Please record the attached original documents or copy thereof:

1. Name of conveying party(ies):

Schlumberger Technologies, Inc.

☐ Individual ☐ Association  
☐ General Partnership ☐ Limited partnership  
☒ Corporation, State of Delaware  
☐ Other: \_\_\_\_\_

Additional name(s) of conveying party(ies) attached?  
☐ Yes ☒ No

2. Name and address of receiving party(ies):

Name: **NPTest, LLC**  
Address: 150 Baytech Drive  
San Jose, California 95134

Additional name(s) of receiving party(ies) attached?  
☐ Yes ☒ No

3. Nature of Conveyance:

☒ Assignment ☐ Merger  
☐ Security Agreement ☐ Change of Name  
☐ Other: \_\_\_\_\_

Execution Date: 5/10/2002

4. Application Number(s) or Patent Number(s):

Attached as Page 2 and Page 3

5. Name and address of party to whom correspondence concerning this document should be mailed:

Name: Frederick D. Kim  
Skadden, Arps, Slate, Meagher & Flom, LLP  
Address: 525 University Avenue, Suite 1100  
Palo Alto, CA 94301

6. Total number of applications and patents involved: 104

7. Total fee (37 C.F.R. § 3.41) (\$40.00 per assignment): \$40.00

☒ Enclosed a check for \$4160.00  
☐ The Commissioner is authorized to charge under-  
payment of any fees or credit any overpayment to  
Deposit Account Number: \_\_\_\_\_

8. Deposit Account Number: \_\_\_\_\_

DO NOT USE THIS SPACE

9. Statement and signature.

To the best of my knowledge and belief, the foregoing information is true and correct and any attached copy is a true copy of the original document.

Frederick D. Kim  
Frederick D. Kim (Reg. No. 38,513)

6/23/03  
Date

Total number of pages including cover sheet, attachments and document: 28Mail documents to be recorded with  
required cover sheet information to:Commissioner of Patents and Trademarks  
Box Assignments  
Washington, D.C. 20231

06/26/2003 ECOOPER 00000125 4594544

01 FC:3021.

4160.00 CP

**Item 4. Attachment**

**Patent Numbers:**

1.	4,594,544	43.	5,747,818
2.	4,623,802	44.	5,748,124
3.	4,651,038	45.	5,821,549
4.	4,673,917	46.	5,840,630
5.	4,706,019	47.	5,883,905
6.	4,721,909	48.	5,892,949
7.	4,795,984	49.	5,905,266
8.	4,864,228	50.	5,905,577
9.	4,864,228	51.	5,913,022
10.	4,910,698	52.	5,918,198
11.	4,912,405	53.	5,920,073
12.	5,054,097	54.	5,944,846
13.	5,091,693	55.	5,959,458
14.	5,122,988	56.	5,996,099
15.	5,127,064	57.	6,006,346
16.	5,140,164	58.	6,014,764
17.	5,144,225	59.	6,031,229
18.	5,210,487	60.	6,049,900
19.	5,212,443	61.	6,061,815
20.	5,225,772	62.	6,078,845
21.	5,235,273	63.	6,081,484
22.	5,270,643	64.	6,128,754
23.	5,287,022	65.	6,181,117
24.	5,357,116	66.	6,225,626
25.	5,392,222	67.	6,252,222
26.	5,401,972	68.	6,263,464
27.	5,430,400	69.	6,285,963
28.	5,461,310	70.	6,410,924
29.	5,475,624	71.	6,420,888
30.	5,477,139	72.	6,462,814
31.	5,481,550	73.	6,492,797
32.	5,530,372	74.	6,496,261
33.	5,604,819	75.	6,496,953
34.	5,616,921	76.	6,501,706
35.	5,638,005	77.	6,501,288
36.	5,646,521	78.	6,514,866
37.	5,654,657	79.	6,518,571
38.	5,673,275	80.	6,522,162
39.	5,675,499	81.	6,553,522
40.	5,700,526		
41.	5,731,984		
42.	5,745,003		



**Item 4. Attachment**

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7. 09/676,292
8. 09/675,981
9. 09/679,042
10. 09/696,102
11. 09/746,618
12. 09/924,736
13. 10/004,018
14. 10/056,287
15. 10/057,134
16. 10/066,123
17. 10/079,780
18. 10/101,564
19. 10/102,526
20. 10/106,280
21. 10/123,842
22. 10/421,059
23. 10/136,710

**RECORDATION FORM COVER SHEET  
PATENTS ONLY**

U.S. Department of Commerce  
Patent and Trademark Office

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☐ General Partnership       ☐ Limited partnership  
☒ Corporation, State of Delaware  
☐ Other: \_\_\_\_\_

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           **San Jose, California 95134**

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20.	5,225,772	62.	6,078,845
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25.	5,392,222	67.	6,252,222
26.	5,401,972	68.	6,263,464
27.	5,430,400	69.	6,285,963
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29.	5,475,624	71.	6,420,888
30.	5,477,139	72.	6,462,814
31.	5,481,550	73.	6,492,797
32.	5,530,372	74.	6,496,261
33.	5,604,819	75.	6,496,953
34.	5,616,921	76.	6,501,706
35.	5,638,005	77.	6,501,288
36.	5,646,521	78.	6,514,866
37.	5,654,657	79.	6,518,571
38.	5,673,275	80.	6,522,162
39.	5,675,499	81.	6,553,522
40.	5,700,526		
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42.	5,745,003		

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2. 09/410,569
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8. 09/675,981
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11. 09/746,618
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17. 10/079,780
18. 10/101,564
19. 10/102,526
20. 10/106,280
21. 10/123,842
22. 10/421,059
23. 10/136,710



**ACKNOWLEDGEMENT  
OF  
SCHLUMBERGER TECHNOLOGIES, INC.**

This Acknowledgement ("Acknowledgement") of Schlumberger Technologies, Inc., a Delaware corporation (the "Assignor") made, executed and delivered as of June 23, 2003 makes reference to that certain General Assignment and Assumption Agreement, dated as of May 10, 2002 and attached hereto as Annex 1 (the "Assignment"), by and between the Assignor and NPTest, LLC, a Delaware limited liability company, formerly Schlumberger Technology Solutions LLC ("NPT" or the "Assignee").

**WITNESSETH:**

WHEREAS, pursuant to the Assignment, Assignor granted, sold, conveyed, assigned and delivered to Assignee all of the assets described on Schedule 1 thereto, including but not limited to all of the intellectual property of the Semiconductor Solutions Group of Assignor relating to Assignor's Test, Probe and SABER business segments, the goodwill associated therewith, licenses and sublicenses granted and obtained with respect thereto, and rights thereunder, remedies against infringement thereof, and rights to protection of interests therein under the laws of all jurisdictions (the "Assigned IP");

WHEREAS, the Assignor desires to acknowledge that certain patents and patent applications owned by Assignor as of May 10, 2002 and listed on Schedule A hereto, including all inventions disclosed and/or claimed therein, all patents that may issue therefrom and the right to sue for past and future infringement thereof, are included in the Assigned IP that was assigned by the Assignor to the Assignee pursuant to the Assignment; and

WHEREAS, the Assignor desires to acknowledge that certain trademarks and service marks owned by Assignor as of May 10, 2002 and listed on Schedule B hereto, including the goodwill symbolized thereby and associated therewith, the registrations and applications for registration thereof, and the right to sue for past and future infringement thereof, are included in the Assigned IP that was assigned by the Assignor to the Assignee.

NOW THEREFORE, Assignor hereby acknowledges the following:


1. The patents and patent applications listed on Schedule A hereto, including all inventions disclosed and/or claimed therein, all patents that may issue therefrom and the right to sue for past and future infringement thereof, are included in the Assigned IP that was assigned by Assignor to NPT pursuant to the Assignment.
2. The trademarks and service marks listed on Schedule B hereto, including the goodwill symbolized thereby and associated therewith, the

registrations and applications for registration thereof, and the right to sue for past and future infringement thereof, are included in the Assigned IP that was assigned by the Assignor to NPT pursuant to the Assignment.

This instrument shall be construed and enforced in accordance with the laws of the State of Delaware (regardless of the laws that might be applicable under principles of conflicts of law) as to all matters, including but not limited to matters of validity, construction, effect and performance.

IN WITNESS WHEREOF, the undersigned, being a duly authorized officer of Assignor, has executed this Acknowledgement for and on behalf of Assignor as of this 23rd day of June 2003.

SCHLUMBERGER TECHNOLOGIES, INC.

By:   
Name: Roland Ewubare

# Schedule A

Patents:

Country	Patent No.	Grant Date	App. Date	Title	Docket
U.S.	4,594,544	10-Jun-86	07-Mar-83	PARTICIPATE REGISTER FOR PARALLEL LOADING PIN-ORIENTED REGISTERS IN TEST EQUIPMENT	65.0081
U.S.	4,623,802	18-Nov-86	17-May-84	MULTIPLE-STAGE GATE NETWORK HAVING INDEPENDENT REFERENCE VOLTAGE SOURCES	65.0118
U.S.	4,651,038	17-Mar-87	17-May-84	GATE HAVING TEMPERATURE-STABILIZED DELAY	65.0117
U.S.	4,672,917	16-Jun-87	18-Jul-84	METHOD AND APPARATUS FOR MINIMIZING DIGITAL-TO-ANALOG CONVERTER CORRECTION TRIMS	65.0120
U.S.	4,706,019	10-Nov-87	15-Nov-85	ELECTRON BEAM TEST PROBE SYSTEM FOR ANALYZING INTEGRATED CIRCUITS	65.0132
U.S.	4,721,909	26-Jan-88	10-Feb-86	APPARATUS FOR PULSING ELECTRON BEAMS	65.0133
U.S.	4,795,984	30-Jan-89	19-Nov-86	MULTI-MARKER, MULTI-DESTINATION TIMING SIGNAL GENERATOR	65.0125
U.S.	4,864,228	05-Sep-89	16-Aug-85	ELECTRON BEAM TEST PROBE FOR INTEGRATED CIRCUIT TESTING	65.0135
U.S.	4,864,228	05-Sep-89	16-Aug-85	ELECTRON BEAM TEST PROBE FOR INTEGRATED CIRCUIT TESTING	65.0150
U.S.	4,910,698	20-Mar-90	12-Dec-88	SINE WAVE GENERATOR USING A CORDIC ALGORITHM	65.0128
U.S.	4,912,405	27-Mar-90	17-May-88	MAGNETIC LENS AND ELECTRON BEAM DEFLECTION SYSTEM	65.0135
U.S.	5,054,097	01-Oct-91	13-Nov-88	METHODS AND APPARATUS FOR ALIGNMENT OF IMAGES	65.0165
U.S.	5,091,693	25-Feb-92	13-Jul-90	DUAL-SIDED TEST HEAD HAVING FLOATING CONTACT SURFACES	65.0180
U.S.	5,122,988	16-Jun-92	17-Jul-91	DATA STREAM SMOOTHING USING A FIFO MEMORY	65.0172
U.S.	5,127,064	30-Jun-92	13-Feb-91	HIGH RESOLUTION IMAGE COMPRESSION METHODS AND APPARATUS	65.0164
U.S.	5,140,164	18-Aug-92	14-Jan-91	IC MODIFICATION WITH FOCUSED ION BEAM	65.0189
U.S.	5,144,225	01-Sep-92	25-Jul-91	METHODS AND APPARATUS FOR ACQUIRING DATA FROM INTERMITTENTLY FAILING CIRCUITS	65.0173
U.S.	5,210,487	11-May-93	04-Jun-91	DOUBLE-GATED INTEGRATING SCHEME FOR ELECTRON BEAM TESTER	65.0191
U.S.	5,212,443	18-May-93	05-Sep-90	Event Sequencer for Automatic Test Equipment	65.0148
U.S.	5,225,772	06-Jul-93	05-Sep-90	AUTOMATIC TEST EQUIPMENT SYSTEM USING PIN SLICE ARCHITECTURE	65.0168
U.S.	5,235,273	10-Aug-93	12-Jul-91	APPARATUS FOR SETTING PIN DRIVER/SENSOR REFERENCE VOLTAGE LEVEL	65.0194
U.S.	5,270,643	14-Dec-93	12-Aug-92	PULSED LASER PHOTOEMISSION ELECTRON-BEAM PROBE	65.0188

Country	Patent No.	Grant Date	App. Date	Title	Doc. No.
U.S.	5,287,022	15-Feb-94	24-Mar-93	METHOD AND CIRCUIT FOR CONTROLLING VOLTAGE REFLECTIONS ON TRANSMISSION LINES	65.0193
U.S.	5,357,116	18-Oct-94	23-Nov-92	FOCUSED ION BEAM PROCESSING WITH CHARGE CONTROL	65.0204
U.S.	5,392,222	21-Feb-95	30-Dec-91	LOCATING A FIELD OF VIEW IN WHICH SELECTED IC CONDUCTORS ARE UNOBSCURED	65.0184
U.S.	5,401,972	28-Mar-95	02-Sep-93	LAYOUT OVERLAY FOR FIB OPERATIONS	65.0210
U.S.	5,430,400	04-Jul-95	03-Aug-93	DRIVER CIRCUITS FOR IC TESTER	65.0209
U.S.	5,461,310	24-Oct-95	28-Jun-94	AUTOMATIC TEST EQUIPMENT SYSTEM USING PIN SLICE ARCHITECTURE	65.0168
U.S.	5,475,624	12-Dec-95	30-Apr-92	TEST GENERATION BY ENVIRONMENT EMULATION	65.0192
U.S.	5,477,139	19-Dec-95	13-May-93	Event Sequencer for Automatic Test Equipment	65.0148
U.S.	5,481,550	02-Jan-96	12-Oct-93	APPARATUS FOR MAINTAINING STIMULATION TO A DEVICE UNDER TEST AFTER A TEST STOPS	65.0203
U.S.	5,530,372	25-Jun-96	15-Apr-94	METHOD OF PROBING A NET OF AN IC AT AN OPTIMAL PROBE-POINT	65.0211
U.S.	5,604,819	18-Feb-97	15-Mar-93	DETERMINING OFFSET BETWEEN IMAGES OF AN IC	65.0202
U.S.	5,616,921	01-Apr-97	30-Jun-94	SELF-MASKING FIB MILLING	65.0207
U.S.	5,638,005	10-Jun-97	08-Jun-95	Predictive Waveform Acquisition	65.0216
U.S.	5,646,521	08-Jul-97	01-Aug-95	ANALOG CHANNEL FOR MIXED-SIGNAL-VLSI TESTER	65.0222
U.S.	5,654,657	05-Aug-97	01-Aug-95	ACCURATE ALIGNMENT OF CLOCKS IN MIXED-SIGNAL TESTER	65.0228
U.S.	5,673,275	30-Sep-97	13-Aug-96	ACCELERATED MODE TESTER TIMING	65.0220
U.S.	5,675,499	07-Oct-97	02-Apr-96	METHOD OF PROBING A NET OF AN IC AT AN OPTIMAL PROBE-POINT	65.0211
U.S.	5,700,526	23-Dec-97	04-May-95	INSULATOR DEPOSITION USING FOCUSED ION BEAM	65.0234
U.S.	5,731,984	28-Mar-98	17-Jul-95	VECTOR-BASED WAVEFORM ACQUISITION AND DISPLAY	65.0239
U.S.	5,745,003	28-Apr-98	11-Sep-96	DRIVER CIRCUITS FOR IC TESTER	65.0243
U.S.	5,747,818	05-May-98	21-Oct-96	THERMOELECTRIC COOLING GAS-ASSISTED FIB SYSTEM	65.0245
U.S.	5,748,124	05-May-98	09-Dec-96	ANALOG CHANNEL FOR MIXED-SIGNAL-VLSI TESTER	65.0222
U.S.	5,821,549	13-Oct-98	03-Mar-97	Through the Substrate Investigation of Flip-Chip ICs	65.0246
U.S.	5,840,630	24-Nov-98	20-Dec-96	FIB ETCHING ENHANCED WITH 1,2 DI-IODO-ETHANE	65.0244
U.S.	5,883,905	16-Mar-99	18-Feb-97	PATTERN GENERATOR WITH EXTENDED REGISTER PROGRAMMING	65.0266
U.S.	5,892,949	06-Apr-99	30-Aug-96	ATE TEST PROGRAMMING ARCHITECTURE	65.0233
U.S.	5,905,266	18-May-99	19-Dec-96	CHARGED PARTICLE BEAM SYSTEM WITH OPTICAL MICROSCOPE	65.0248
U.S.	5,905,577	18-May-99	15-Mar-97	DUAL-LASER VOLTAGE PROBING OF IC'S	65.0261
U.S.	5,913,022	15-Jun-99	15-Dec-95	LOADING HARDWARE PATTERN MEMORY IN AUTOMATIC TEST EQUIPMENT FOR	65.0231



Country	Patent No.	Grant Date	App. Date	Title	Doc.
				TESTING CIRCUITS	
U.S.	5,918,198	29-Jun-99	22-Oct-96	GENERATING PULSES IN ANALOG CHANNEL OF ATE TESTER	65.0252
U.S.	5,920,073	06-Jul-99	22-Apr-97	OPTICAL SYSTEM WITH AN AXIALLY MOVEABLE APERTURED PLATE	65.0262
U.S.	5,944,846	31-Aug-99	30-Sep-97	Method and Apparatus for Selectively Testing Identical Pins of a Plurality of Electronic Components	65.0238
U.S.	5,959,458	28-Sep-99	08-Nov-96	METHOD AND APPARATUS FOR MEASURING ELECTRICAL WAVEFORMS USING ATOMIC FORCE MICROSCOPY	65.0253
U.S.	5,996,099	30-Nov-99	30-Sep-97	METHOD AND APPARATUS FOR AUTOMATICALLY TESTING ELECTRONIC COMPONENTS IN PARALLEL UTILIZING DIFFERENT TIMING SIGNALS FOR EACH ELECTRONIC COMPONENT	65.0236
U.S.	6,006,346	21-Dec-99	14-May-97	Method and Equipment for Automatically Testing Electronic Components	65.0221
U.S.	6,014,764	11-Jan-00	20-May-97	PROVIDING TEST VECTORS WITH PATTERN CHAINING DEFINITION	65.0254
U.S.	6,031,229	29-Feb-00	20-May-98	AUTOMATIC SEQUENCING OF FIB OPERATIONS	65.0269
U.S.	6,049,900	11-Apr-00	30-Sep-97	AUTOMATIC PARALLEL ELECTRONIC COMPONENT TESTING METHOD AND EQUIPMENT	65.0237
U.S.	6,061,815	09-May-00	09-Dec-96	PROGRAMMING UTILITY REGISTER TO GENERATE ADDRESSES IN ALGORITHMIC PATTERN GENERATOR	65.0247
U.S.	6,078,845	20-Jun-00	25-Nov-96	APPARATUS FOR CARRYING SEMICONDUCTOR DEVICES	65.0257
U.S.	6,081,484	27-Jun-00	14-Oct-97	Measuring Signals in a Tester System	65.0274
U.S.	6,128,754	03-Oct-00	24-Nov-97	AUTOMATIC CIRCUIT TESTER HAVING A WAVEFORM ACQUISITION MODE OF OPERATION	65.0271
U.S.	6,181,117	30-Jan-01	25-Oct-99	POWER SUPPLY CIRCUIT OF AN ELECTRONIC COMPONENT IN A TEST MACHINE	65.0264
U.S.	6,225,626	01-May-01	30-Sep-98	Through the Substrate Investigation of Flip-Chip ICs	65.0246
U.S.	6,252,222	26-Jun-01	13-Jan-00	Differential Pulsed Laser Beam Probing of Integrated Circuits	65.0312
U.S.	6,263,464	17-Jul-01	22-Apr-99	DEVICE FOR CONTROLLING CONFORMITY OF CONSUMPTION OF AN ELECTRONIC COMPONENT IN A TESTING MACHINE	65.0263
U.S.	6,285,963	04-Sep-01	30-Nov-99	Measuring Signals in a Tester System	65.0274
U.S.	6,410,924	25-Jun-02	16-Nov-99	Energy Filtered Focused Ion Beam Column	65.0281
U.S.	6,420,888	16-Jul-02	29-Sep-00	Test Interface Module	65.0339
U.S.	6,462,814	08-Oct-02	15-Mar-00	BEAM DELIVERY AND IMAGING FOR OPTICAL PROBING OF A DEVICE OPERATING UNDER ELECTRICAL TEST	65.0267
U.S.	6,492,797	10-Dec-02	28-Feb-00	Socket Calibration Method and Apparatus	65.0302

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U.S.	6,496,261	17-Dec-02	08-Feb-00	Double-Pulsed Optical Interferometer for Waveform Probing of Integrated Circuits	65.0316
U.S.	6,496,953	17-Dec-02	15-Mar-00	Calibration Method and Apparatus for Correcting Pulse Width Timing Errors in Integrated Circuit Testing	65.0307
U.S.	6,501,706	31-Dec-02	22-Aug-00	TIME-TO-DIGITAL CONVERTER	65.0296
U.S.	6,501,288	31-Dec-02	28-Sep-00	On-Chip Optically Triggered Latch for IC Time Measurements	65.0324
U.S.	6,514,866	04-Feb-03	31-May-01	Chemical Enhanced Focused Ion Beam Micro-Machining of Copper	65.0345
U.S.	6,518,571	11-Feb-03	10-Feb-01	Through the Substrate Investigation of Flip-Chip ICs	65.0246
U.S.	6,522,162	18-Feb-03	24-Apr-02	Test System Having Interface Module	65.0339
U.S.	6,553,522	22-Apr-03	22-Feb-00	Valuation of Tester Accuracy	65.0303
Canada	1256587	27-Jun-89	10-Nov-86	ELECTRON BEAM TEST PROBE SYSTEM FOR ANALYZING INTEGRATED CIRCUITS	65.0132
Canada	1256597	27-Jun-89	06-Feb-87	APPARATUS FOR PULSING ELECTRON BEAMS	65.0133
Canada	1271997	24-Jul-90	14-Mar-86	ELECTRON BEAM TEST PROBE FOR INTEGRATED CIRCUIT TESTING	65.0150
France	8308129	28-Jul-86	17-May-83	Test System Memory Architecture for Passing	65.0077
France	0390675	12-Apr-95	28-Mar-90	METHODS AND APPARATUS FOR ACQUIRING DATA FROM INTERMITTENTLY FAILING CIRCUITS	65.0173
France	0599367	15-May-96	02-Nov-93	FOCUSED ION BEAM PROCESSING WITH CHARGE CONTROL	65.0204
France	0492677	12-Jun-96	24-Oct-91	PULSED LASER PHOTOEMISSION ELECTRON-BEAM PROBE	65.0188
France	FR91 08845	12-Jul-96	12-Jul-91	DUAL-SIDED TEST HEAD HAVING FLOATING CONTACT SURFACES	65.0180
France	0474275	15-Jan-97	12-Aug-91	AUTOMATIC TEST EQUIPMENT SYSTEM USING PIN SLICE ARCHITECTURE	65.0168
France	0474274	02-Apr-97	12-Aug-91	Event Sequencer for Automatic Test Equipment	65.0148
France	0517294	02-Jul-97	20-May-92	DOUBLE-GATED INTEGRATING SCHEME FOR ELECTRON BEAM TESTER	65.0191
France	0370323	09-Jul-97	09-Nov-89	HIGH RESOLUTION IMAGE COMPRESSION METHODS AND APPARATUS	65.0164
France	2738640	31-Oct-97	12-Sep-96	ACCELERATED MODE TESTER TIMING	65.0220
France	2756380	29-May-98	25-Nov-96	DEVICE FOR CONTROLLING CONFIRMITY OF CONSUMPTION OF AN ELECTRONIC COMPONENT IN A TESTING MACHINE	65.0263
France	0370322	08-Jul-98	09-Nov-89	METHODS AND APPARATUS FOR ALIGNMENT OF IMAGES	65.0165
France	2737620	07-Aug-98	01-Aug-96	ACCURATE ALIGNMENT OF CLOCKS IN MIXED-SIGNAL TESTER	65.0228
France	0 800676	19-Aug-98	20-Dec-95	Method and Equipment for Automatically Testing Electronic Components	65.0221
France	2709351	30-Oct-98	02-Aug-94	DRIVER CIRCUITS FOR IC TESTER	65.0209
France	2753273	22-Jan-99	08-Sep-97	DRIVER CIRCUITS FOR IC TESTER	65.0243
France	2759460	16-Apr-99	13-Feb-97	POWER SUPPLY CIRCUIT OF AN ELECTRONIC COMPONENT IN A TEST MACHINE	65.0264

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France	0619551	12-Jan-00	07-Mar-94	DETERMINING OFFSET BETWEEN IMAGES OF AN IC	65.0202
France	0855734	29-Nov-00	10-Dec-97	FIB ETCHING ENHANCED WITH 1,2 DI-IODO-ETHANE	65.0244
France	2781066	02-May-02	09-Jul-98	SECURING DATA IN A MACHINE FOR TESTING ELECTRONIC COMPONENTS	65.0291
France	2806527	25-Oct-02	20-Mar-00	Column Simultaneously Focusing a Particle Beam and an Optical Beam	65.0290
France	2779009	03-Jan-03	10-May-02	AUTOMATIC SEQUENCING OF FIB OPERATIONS	65.0269
Germany	0599367	15-May-96	02-Nov-93	FOCUSED ION BEAM PROCESSING WITH CHARGE CONTROL	65.0204
Germany	69120233.8	12-Jun-96	24-Oct-91	PULSED LASER PHOTOEMISSION ELECTRON-BEAM PROBE	65.0188
Germany	0517294	02-Jul-97	20-May-92	DOUBLE-GATED INTEGRATING SCHEME FOR ELECTRON BEAM TESTER	65.0191
Germany	P3688612.2	09-Jul-97	09-Nov-89	HIGH RESOLUTION IMAGE COMPRESSION METHODS AND APPARATUS	65.0164
Germany	3317593	20-May-98	14-May-83	Test System Memory Architecture for Passing	65.0077
Germany	68928726	08-Jul-98	09-Nov-89	METHODS AND APPARATUS FOR ALIGNMENT OF IMAGES	65.0165
Germany	69422539.8-08	12-Jan-00	07-Mar-94	DETERMINING OFFSET BETWEEN IMAGES OF AN IC	65.0202
Germany	69703611.1	29-Nov-00	10-Dec-97	FIB ETCHING ENHANCED WITH 1,2 DI-IODO-ETHANE	65.0244
Germany	19629869	13-Feb-03	24-Jul-96	ACCURATE ALIGNMENT OF CLOCKS IN MIXED-SIGNAL TESTER	65.0228
Italy	0599367	15-May-96	02-Nov-93	FOCUSED ION BEAM PROCESSING WITH CHARGE CONTROL	65.0204
Italy	0474275	15-Jan-97	12-Aug-91	AUTOMATIC TEST EQUIPMENT SYSTEM USING PIN SLICE ARCHITECTURE	65.0168
Italy	0517294	02-Jul-97	20-May-92	DOUBLE-GATED INTEGRATING SCHEME FOR ELECTRON BEAM TESTER	65.0191
Italy	0619551	12-Jan-00	07-Mar-94	DETERMINING OFFSET BETWEEN IMAGES OF AN IC	65.0202
Japan	1988075	08-Nov-95	13-Feb-91	HIGH RESOLUTION IMAGE COMPRESSION METHODS AND APPARATUS	65.0164
Japan	2581815	21-Nov-96	24-Nov-89	METHODS AND APPARATUS FOR ALIGNMENT OF IMAGES	65.0165
Japan	2864647	18-Dec-98	28-Jun-94	SELF-MASKING FIB MILLING	65.0207
Japan	3115108	29-Sep-00	13-Jul-92	APPARATUS FOR SETTING PIN DRIVER/SENSOR REFERENCE VOLTAGE LEVEL	65.0194
Japan	3169232	16-Mar-01	02-Jul-91	DUAL-SIDED TEST HEAD HAVING FLOATING CONTACT SURFACES	65.0180
Japan	3220480	10-Aug-01	04-Sep-91	Event Sequencer for Automatic Test Equipment	65.0148
Japan	3263503	21-Dec-01	22-Nov-93	FOCUSED ION BEAM PROCESSING WITH CHARGE CONTROL	65.0204
Japan	3298653	19-Apr-02	04-Sep-91	AUTOMATIC TEST EQUIPMENT SYSTEM USING PIN SLICE ARCHITECTURE	65.0168
Netherlands	0599367	15-May-96	02-Nov-93	FOCUSED ION BEAM PROCESSING WITH CHARGE CONTROL	65.0204

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Netherlands	0474275	15-Jan-97	12-Aug-91	AUTOMATIC TEST EQUIPMENT SYSTEM USING PIN SLICE ARCHITECTURE	65.0168
Netherlands	0517294	02-Jul-97	20-May-92	DOUBLE-GATED INTEGRATING SCHEME FOR ELECTRON BEAM TESTER	65.0191
Netherlands	0370322	08-Jul-98	09-Nov-89	METHODS AND APPARATUS FOR ALIGNMENT OF IMAGES	65.0165
Netherlands	0619551	12-Jan-00	07-Mar-94	DETERMINING OFFSET BETWEEN IMAGES OF AN IC	65.0202
Taiwan	NI-092318	13-May-98	08-Jun-96	Predictive Waveform Acquisition	65.0216
Taiwan	NI-093673	24-Jul-98	10-Jul-97	METHOD AND APPARATUS FOR MEASURING ELECTRICAL WAVEFORMS USING ATOMIC FORCE MICROSCOPY	65.0253
Taiwan	NI-096415	08-Dec-98	16-Jul-97	GENERATING PULSES IN ANALOG CHANNEL OF ATE TESTER	65.0252
Taiwan	NI-098099	15-Mar-99	28-Jul-97	DRIVER CIRCUITS FOR IC TESTER	65.0243
Taiwan	105657	11-Jun-99	03-Mar-98	POWER SUPPLY CIRCUIT OF AN ELECTRONIC COMPONENT IN A TEST MACHINE	65.0264
Taiwan	NI-104487	01-Jul-99	20-Jan-98	METHOD AND APPARATUS FOR GENERATING SPLIT TIMING TEST SIGNALS FOR INTEGRATED CIRCUIT TESTING	65.0268
Taiwan	NI-107526	01-Oct-99	05-Feb-98	PATTERN GENERATOR WITH EXTENDED REGISTER PROGRAMMING	65.0266
Taiwan	NI-103668	05-Oct-99	03-Dec-97	PROGRAMMING UTILITY REGISTER TO GENERATE ADDRESSES IN ALGORITHMIC PATTERN GENERATOR	65.0247
Taiwan	NI-109360	10-Apr-00	11-Nov-97	FIB ETCHING ENHANCED WITH 1,2 DI-IODO-ETHANE	65.0244
Taiwan	NI-109540	13-Apr-00	21-Oct-97	APPARATUS FOR CARRYING SEMICONDUCTOR DEVICES	65.0257
Taiwan	NI-109745	18-Apr-00	23-Mar-98	PROVIDING TEST VECTORS WITH PATTERN CHAINING DEFINITION	65.0254
Taiwan	NI-120890	01-Oct-00	13-Oct-98	AUTOMATIC CIRCUIT TESTER HAVING A WAVEFORM ACQUISITION MODE OF OPERATION	65.0271
Taiwan	NI-121589	21-Oct-00	30-Jul-97	CHARGED PARTICLE BEAM SYSTEM WITH OPTICAL MICROSCOPE	65.0248
Taiwan	NI-142848	21-Oct-01	13-Oct-98	MEASURING SIGNALS IN A TESTER SYSTEM	65.0274
Taiwan	159509	11-Jul-02	14-Sep-01	Compact, High Collection Efficiency Scintillator for Secondary Electron Detection	65.0322
Taiwan	161277	11-Aug-02	15-Mar-01	BEAM DELIVERY AND IMAGING FOR OPTICAL PROBING OF A DEVICE OPERATING UNDER ELECTRICAL TEST	65.0267
Taiwan	090123901	11-Aug-02	27-Sep-01	Method and Apparatus for Remotely Testing Semiconductor	65.0340
U.K.	2121550B	18-Dec-85	17-May-83	Test System Memory Architecture for Passing	65.0077
U.K.	0390675	12-Apr-95	28-Mar-90	METHODS AND APPARATUS FOR ACQUIRING DATA FROM INTERMITTENTLY FAILING CIRCUITS	65.0173
U.K.	0599367	15-May-96	02-Nov-93	FOCUSED ION BEAM PROCESSING WITH CHARGE CONTROL	65.0204

Country	Patent No.	Grant Date	App. Date	Inv.	Doc.
U.K.	0474275	15-Jan-97	12-Aug-91	AUTOMATIC TEST EQUIPMENT SYSTEM USING PIN SLICE ARCHITECTURE	65.0168
U.K.	0474274	02-Apr-97	12-Aug-91	Event Sequencer for Automatic Test Equipment	65.0148
U.K.	0517294	02-Jul-97	20-May-92	DOUBLE-GATED INTEGRATING SCHEME FOR ELECTRON BEAM TESTER	65.0191
U.K.	2300515	09-Jul-97	17-Apr-96	INSULATOR DEPOSITION USING FOCUSED ION BEAM	65.0234
U.K.	0370322	08-Jul-98	09-Nov-89	METHODS AND APPARATUS FOR ALIGNMENT OF IMAGES	65.0165
U.K.	0 800676	19-Aug-98	20-Dec-95	Method and Equipment for Automatically Testing Electronic Components	65.0221
U.K.	0855734	29-Nov-00	10-Dec-97	FIB ETCHING ENHANCED WITH 1,2 DI- IODO-ETHANE	65.0244

Patent Applications:

Country	App. No.	App. Date	Title	Dosk
U.S.	09/350,611	7/9/99	SECURING DATA IN A MACHINE FOR TESTING ELECTRONIC COMPONENTS	65.0291
U.S.	09/410,569	10/1/99	Test Method and Apparatus for Source Synchronous Signals	65.0309
U.S.	09/419,317	10/17/99	Measuring Jitter of High-Speed Data Channels	65.0299
U.S.	09/421,784	10/19/99	Packet-Based Device Test System	65.0306
U.S.	09/628,116	7/28/00	Superconducting Single Photon Detector	65.0332
U.S.	09/648,716	8/25/00	Edge Placement and Jitter Measurement for Electronic Elements	65.0297
U.S.	09/676,292	9/28/00	Method and Apparatus for Remotely Testing Semiconductor	65.0340
U.S.	09/675,981	9/29/00	Compact, High Collection Efficiency Scintillator for Secondary Electron Detection	65.0322
U.S.	09/679,042	10/2/00	Method and Apparatus for High Speed IC Test Interface	65.0337
U.S.	09/696,102	10/24/00	Scan Stream Sequencing for Testing Integrated Circuits	65.0321
U.S.	09/746,618	12/21/00	Optical Coupling for Testing Integrated Circuits	65.0329
U.S.	09/924,736	8/7/01	Method for Global Die Thinning and Polishing of Flip-Chip Packaged Integrated Circuits	65.0338
U.S.	10/004,018	10/18/01	Photoconductive-Sampling Voltage Measurement	65.0272
U.S.	10/056,287	1/23/02	Circuit and Method for Distributing Events in an Event Stream	65.0363
U.S.	10/057,134	1/24/02	Comparator Circuit for Differential Swing Comparison and Common-Mode Voltage Comparison	65.0364
U.S.	10/066,123	1/30/02	PICA System Timing Measurement & Calibration	65.0372
U.S.	10/079,780	2/19/02	PICA System Detector Calibration	65.0373
U.S.	10/101,564	3/18/02	Test System Formatters	65.0348
U.S.	10/102,526	3/19/02	Test System Algorithmic Program Generators	65.0350
U.S.	10/106,280	3/25/02	Method and Apparatus for Socket Calibration of Integrated Circuit Testers	65.0352
U.S.	10/123,842	4/15/02	Measuring Back-Side Voltage of an Integrated Circuit	65.0354
U.S.	10/421,059	4/23/02	Method for Backside Die Thinning and Polishing of Packaged Integrated Circuits	65.0338
U.S.	10/136,710	4/30/02	Open-Loop for Waveform Acquisition	65.0355
China	01141510.X	9/28/01	Method and Apparatus for Remotely Testing Semiconductor	65.0340
EC	96201465.0	5/28/96	Predictive Waveform Acquisition	65.0216
EC	97/402304.6	10/1/97	THERMOELECTRIC COOLING GAS-ASSISTED FIB SYSTEM	65.0245
EC	97402305.3	10/1/97	METHOD AND APPARATUS FOR MEASURING ELECTRICAL WAVEFORMS USING ATOMIC FORCE MICROSCOPY	65.0253
EC	97/402535.5	10/24/97	CHARGED PARTICLE BEAM SYSTEM WITH OPTICAL MICROSCOPE	65.0248
EC	97402533.0	10/24/97	APPARATUS FOR CARRYING SEMICONDUCTOR DEVICES	65.0257
EC	98/400378.0	2/17/98	PATTERN GENERATOR WITH EXTENDED REGISTER PROGRAMMING	65.0266
EC	98/400441.6	2/23/98	Through the Substrate Investigation of Flip-Chip ICs	65.0246
EC	98/400562.9	3/10/98	DUAL-LASER VOLTAGE PROBING OF IC'S	65.0261
EC	98400789.8	4/2/98	Optical System with an Axially Moveable Apertured Plate	65.0262
EC	98401017.3	4/24/98	PROVIDING TEST VECTORS WITH PATTERN CHAINING DEFINITION	65.0254

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EC	98402555.1	10/14/98	MEASURING SIGNALS IN A TESTER SYSTEM	65.0274
EC	98402769.8	11/6/98	AUTOMATIC CIRCUIT TESTER HAVING A WAVEFORM ACQUISITION MODE OF OPERATION	65.0271
EC	01925126.3	3/15/01	BEAM DELIVERY AND IMAGING FOR OPTICAL PROBING OF A DEVICE OPERATING UNDER ELECTRICAL TEST	65.0267
EC	01204103.4	10/30/01	Method and Apparatus for Remotely Testing Semiconductor	65.0340
France	94/07913	6/28/94	SELF-MASKING FIB MILLING	65.0207
France	94/10272	8/23/94	LAYOUT OVERLAY FOR FIB OPERATIONS	65.0210
France	96/05206	4/23/96	INSULATOR DEPOSITION USING FOCUSED ION BEAM	65.0234
France	96/09712	8/1/96	ANALOG CHANNEL FOR MIXED-SIGNAL-VLSI TESTER	65.0222
France	97/12223	10/1/97	GENERATING PULSES IN ANALOG CHANNEL OF ATE TESTER	65.0252
France	0012079	9/22/00	Double-Pulsed Optical Interferometer for Waveform Probing of Integrated Circuits	65.0316
France	0012525	10/2/00	Test Method and Apparatus for Source Synchronous Signals	65.0309
France	0100299	1/11/01	Differential Pulsed Laser Beam Probing of Integrated Circuits	65.0312
France	0101366	1/31/01	Electric Feeding Device for a Test Installation of Components	65.0353
France	0103388	3/13/01	Calibration Method and Apparatus for Correcting Pulse Width Timing Errors in Integrated Circuit Testing	65.0307
France	0110076	7/27/01	Superconducting Single Photon Detector	65.0332
France	0110993	8/22/01	TIME-TO-DIGITAL CONVERTER	65.0296
France	0111093	8/24/01	EDGE PLACEMENT AND JITTER MEASUREMENT FOR ELECTRONIC ELEMENTS	65.0297
France	0112423	9/27/01	On-Chip Optically Triggered Latch for IC Time Measurements	65.0324
France	0112506	9/28/01	Compact, High Collection Efficiency Scintillator for Secondary Electron Detection	65.0322
France	0113588	10/22/01	Scan Stream Sequencing for Testing Integrated Circuits	65.0321
France	0112656	10/26/01	Method and Apparatus for High Speed IC Test Interface	65.0337
France	0116591	12/20/01	Optical Coupling for Testing Integrated Circuits	65.0329
France	02 03575	3/22/02	Method and Apparatus for Socket Calibration of Integrated Circuit Testers	65.0352
Germany	P4414295.1	4/23/94	APPARATUS FOR MAINTAINING STIMULATION TO A DEVICE UNDER TEST AFTER A TEST STOPS	65.0203
Germany	P4421517.7	6/20/94	SELF-MASKING FIB MILLING	65.0207
Germany	P 4426538.7	7/27/94	Driver Circuits for IC Tester	65.0209
Germany	P4430456.0	8/27/94	LAYOUT OVERLAY FOR FIB OPERATIONS	65.0210
Germany	19513819.8	4/12/95	METHOD OF PROBING A NET OF AN IC AT AN OPTIMAL PROBE-POINT	65.0211
Germany	19617027.3	4/27/96	INSULATOR DEPOSITION USING FOCUSED ION BEAM	65.0234
Germany	19631005.9	8/1/96	ANALOG CHANNEL FOR MIXED-SIGNAL-VLSI TESTER	65.0222
Germany	19636881.2	9/11/96	ACCELERATED MODE TESTER TIMING	65.0220
Germany	19627056.1	7/5/97	VECTOR-BASED WAVEFORM ACQUISITION AND DISPLAY	65.0239
Germany	19922653.9	5/18/99	AUTOMATIC SEQUENCING OF FIB OPERATIONS	65.0269
Germany	19931047.5	7/6/99	SECURING DATA IN A MACHINE FOR TESTING ELECTRONIC COMPONENTS	65.0291
Germany	19950506.3	10/20/99	MEASURING JITTER OF HIGH-SPEED DATA CHANNELS	65.0299
Germany	10047136.6	9/22/00	Double-Pulsed Optical Interferometer for Waveform Probing of Integrated Circuits	65.0316
Germany	10048895.1	10/2/00	Test Method and Apparatus for Source Synchronous Signals	65.0309

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Germany	10100816.3	1/10/01	Differential Pulsed Laser Beam Probing of Integrated Circuits	65.0312
Germany	10109385.3	2/27/01	Socket Calibration Method and Apparatus	65.0302
Germany	10112311.6	3/14/01	Calibration Method and Apparatus for Correcting Pulse Width Timing Errors in Integrated Circuit Testing	65.0307
Germany	01919529.6	3/19/01	Column Simultaneously Focusing a Particle Beam and an Optical Beam	65.0290
Germany	10141070.0	8/22/01	TIME-TO-DIGITAL CONVERTER	65.0296
Germany	10141523.0	8/24/01	EDGE PLACEMENT AND JITTER MEASUREMENT FOR ELECTRONIC ELEMENTS	65.0297
Germany	10147298.6	9/26/01	Method and Apparatus for High Speed IC Test Interface	65.0337
Germany	10147652.3	9/27/01	On-Chip Optically Triggered Latch for IC Time Measurements	65.0324
Germany	10147995.6	9/28/01	Compact, High Collection Efficiency Scintillator for Secondary Electron Detection	65.0322
Germany	10150321.0	10/11/01	Scan Stream Sequencing for Testing Integrated Circuits	65.0321
Germany	10162222.8	12/18/01	Optical Coupling for Testing Integrated Circuits	65.0329
Germany	10136679.5	2/7/02	Superconducting Single Photon Detector	65.0332
Germany	10212617.8	3/21/02	Method and Apparatus for Socket Calibration of Integrated Circuit Testers	65.0352
Italy	01919529.6	3/19/01	Column Simultaneously Focusing a Particle Beam and an Optical Beam	65.0290
Japan	6-90015	4/27/94	APPARATUS FOR MAINTAINING STIMULATION TO A DEVICE UNDER TEST AFTER A TEST STOPS	65.0203
Japan	6-182089	8/3/94	DRIVER CIRCUITS FOR IC TESTER	65.0209
Japan	6-210030	9/2/94	LAYOUT OVERLAY FOR FIB OPERATIONS	65.0210
Japan	7-91090	4/17/95	METHOD OF PROBING A NET OF AN IC AT AN OPTIMAL PROBE-POINT	65.0211
Japan	8-531508	4/10/96	AUTOMATIC PARALLEL ELECTRONIC COMPONENT TESTING METHOD AND EQUIPMENT	65.0237
Japan	8-112683	5/7/96	INSULATOR DEPOSITION USING FOCUSED ION BEAM	65.0234
Japan	8-147393	6/10/96	Predictive Waveform Acquisition	65.0216
Japan	8-187670	7/17/96	VECTOR-BASED WAVEFORM ACQUISITION AND DISPLAY	65.0239
Japan	8-203773	8/1/96	Analog Channel for Mixed-Signal VLSI Tester	65.0222
Japan	8-203824	8/1/96	Accurate Alignment of Clocks in Mixed-Signal Tester	65.0228
Japan	8-240710	9/11/96	ACCELERATED MODE TESTER TIMING	65.0220
Japan	9-246703	9/11/97	DRIVER CIRCUITS FOR IC TESTER	65.0243
Japan	9-288580	10/21/97	THERMOELECTRIC COOLING GAS-ASSISTED FIB SYSTEM	65.0245
Japan	9-289374	10/22/97	GENERATING PULSES IN ANALOG CHANNEL OF ATE TESTER	65.0252
Japan	9-307449	11/10/97	METHOD AND APPARATUS FOR MEASURING ELECTRICAL WAVEFORMS USING ATOMIC FORCE MICROSCOPY	65.0253
Japan	9-323311	11/25/97	APPARATUS FOR CARRYING SEMICONDUCTOR DEVICES	65.0257
Japan	9-338419	12/9/97	PROGRAMMING UTILITY REGISTER TO GENERATE ADDRESSES IN ALGORITHMIC PATTERN GENERATOR	65.0247
Japan	9-345286	12/15/97	FIB ETCHING ENHANCED WITH 1,2 DI-IODO-ETHANE	65.0244
Japan	9-344985	12/15/97	CHARGED PARTICLE BEAM SYSTEM WITH OPTICAL MICROSCOPE	65.0248
Japan	10-36225	2/18/98	PATTERN GENERATOR WITH EXTENDED REGISTER	65.0266



Country	App. No.	App. Date	Title	Index
			PROGRAMMING	
Japan	10-51060	3/3/98	Through the Substrate Investigation of Flip-Chip ICs	65.0246
Japan	10-65834	3/16/98	DUAL-LASER VOLTAGE PROBING OF IC'S	65.0261
Japan	10-111250	4/22/98	OPTICAL SYSTEM WITH AN AXIALLY MOVEABLE APERTURED PLATE	65.0262
Japan	10-138281	5/20/98	PROVIDING TEST VECTORS WITH PATTERN CHAINING DEFINITION	65.0254
Japan	10-292303	10/14/98	MEASURING SIGNALS IN A TESTER SYSTEM	65.0274
Japan	10-332748	11/24/98	AUTOMATIC CIRCUIT TESTER HAVING A WAVEFORM ACQUISITION MODE OF OPERATION	65.0271
Japan	11-140173	5/20/99	AUTOMATIC SEQUENCING OF FIB OPERATIONS	65.0269
Japan	11-189015	7/2/99	SECURING DATA IN A MACHINE FOR TESTING ELECTRONIC COMPONENTS	65.0291
Japan	11-298939	10/20/99	MEASURING JITTER OF HIGH-SPEED DATA CHANNELS	65.0299
Japan	2000-288647	9/22/00	Double-Pulsed Optical Interferometer for Waveform Probing of Integrated Circuits	65.0316
Japan	2000-302945	10/2/00	Test Method and Apparatus for Source Synchronous Signals	65.0309
Japan	2000-316082	10/17/00	Packet-Based Device Test System	65.0306
Japan	2000-384490	11/13/00	Energy Filtered Focused Ion Beam Column	65.0281
Japan	2001-668	1/5/01	Differential Pulsed Laser Beam Probing of Integrated Circuits	65.0312
Japan	2001-31019	2/7/01	Socket Calibration Method and Apparatus	65.0302
Japan	2001-67243	3/9/01	Calibration Method and Apparatus for Correcting Pulse Width Timing Errors in Integrated Circuit Testing	65.0307
Japan	2001-568039	3/15/01	BEAM DELIVERY AND IMAGING FOR OPTICAL PROBING OF A DEVICE OPERATING UNDER ELECTRICAL TEST	65.0267
Japan	2001-221971	7/23/01	Superconducting Single Photon Detector	65.0332
Japan	2001-252061	8/22/01	TIME-TO-DIGITAL CONVERTER	65.0296
Japan	2001-252110	8/22/01	EDGE PLACEMENT AND JITTER MEASUREMENT FOR ELECTRONIC ELEMENTS	65.0297
Japan	2001-287506	9/20/01	Method and Apparatus for Remotely Testing Semiconductor	65.0340
Japan	2001-303480	9/28/01	Compact, High Collection Efficiency Scintillator for Secondary Electron Detection	65.0322
Japan	2001-303461	9/28/01	On-Chip Optically Triggered Latch for IC Time Measurements	65.0324
Japan	2001-305733	10/1/01	Method and Apparatus for High Speed IC Test Interface	65.0337
Japan	2001-323752	10/22/01	Scan Stream Sequencing for Testing Integrated Circuits	65.0321
Japan	2001-390123	12/21/01	Optical Coupling for Testing Integrated Circuits	65.0329
Japan	2001-81349	3/22/02	Method and Apparatus for Socket Calibration of Integrated Circuit Testers	65.0352
Malaysia	PI9801199	3/19/98	PROVIDING TEST VECTORS WITH PATTERN CHAINING DEFINITION	65.0254
PCT	PCT/FR97/01987	11/6/97	DEVICE FOR CONTROLLING CONFIRMITY OF CONSUMPTION OF AN ELECTRONIC COMPONENT IN A TESTING MACHINE	65.0263
PCT	PCT/FR98/00245	2/9/98	POWER SUPPLY CIRCUIT OF AN ELECTRONIC COMPONENT IN A TEST MACHINE	65.0264
PCT	PCT/IB02/00263	1/29/02	Electric Feeding Device for a Test Installation of Components	65.0353

Country	App. No.	App. Date	Title	Doc.
PCT	PCT/US02/07305	3/11/02	Method for Global Die Thinning and Polishing of Flip-Chip Packaged Integrated Circuits	65.0338
PCT	PCT/US02/08427	3/18/02	Test System Formatters	65.0348
PCT	PCT/US02/08627	3/19/02	Low-Jitter Clock for Test System	65.0349
PCT	PCT/US02/08539	3/19/02	Test System Algorithmic Program Generators	65.0350
PCT	PCT/US02/12109	4/16/02	Measuring Back-Side Voltage of an Integrated Circuit	65.0354
PCT	PCT/US02/13649	4/30/02	Open-Loop for Waveform Acquisition	65.0355
S. Korea	32178/96	7/18/96	ANALOG CHANNEL FOR MIXED-SIGNAL-VLSI TESTER	65.0222
S. Korea	32177/96	8/1/96	ACCURATE ALIGNMENT OF CLOCKS IN MIXED-SIGNAL TESTER	65.0228
S. Korea	38878/96	9/9/96	ACCELERATED MODE TESTER TIMING	65.0220
S. Korea	40545/97	8/25/97	GENERATING PULSES IN ANALOG CHANNEL OF ATE TESTER	65.0252
S. Korea	41268/97	8/26/97	CHARGED PARTICLE BEAM SYSTEM WITH OPTICAL MICROSCOPE	65.0248
S. Korea	42058/97	8/28/97		65.0243
S. Korea	44675/97	8/30/97	METHOD AND APPARATUS FOR MEASURING ELECTRICAL WAVEFORMS USING ATOMIC FORCE MICROSCOPY	65.0253
S. Korea	60724/97	11/18/97	APPARATUS FOR CARRYING SEMICONDUCTOR DEVICES	65.0257
S. Korea	66467/97	12/6/97	PROGRAMMING UTILITY REGISTER TO GENERATE ADDRESSES IN ALGORITHMIC PATTERN GENERATOR	65.0247
S. Korea	70005/97	12/17/97	FIB ETCHING ENHANCED WITH 1,2 DI-IODO-ETHANE	65.0244
S. Korea	7006327/99	2/9/98	POWER SUPPLY CIRCUIT OF AN ELECTRONIC COMPONENT IN A TEST MACHINE	65.0264
S. Korea	4724/98	2/17/98	PATTERN GENERATOR WITH EXTENDED REGISTER PROGRAMMING	65.0266
S. Korea	14126/98	4/21/98	OPTICAL SYSTEM WITH AN AXIALLY MOVEABLE APERTURED PLATE	65.0262
S. Korea	17910/98	5/19/98	PROVIDING TEST VECTORS WITH PATTERN CHAINING DEFINITION	65.0254
S. Korea	50368/98	11/24/98	AUTOMATIC CIRCUIT TESTER HAVING A WAVEFORM ACQUISITION MODE OF OPERATION	65.0271
S. Korea	55963/2000	9/23/00	Double-Pulsed Optical Interferometer for Waveform Probing of Integrated Circuits	65.0316
S. Korea	0057947/2000	10/2/00	Test Method and Apparatus for Source Synchronous Signals	65.0309
S. Korea	0001728/2001	1/12/01	Differential Pulsed Laser Beam Probing of Integrated Circuits	65.0312
S. Korea	00086118/2001	2/21/01	Socket Calibration Method and Apparatus	65.0302
S. Korea	0013100/2001	3/14/01	Calibration Method and Apparatus for Correcting Pulse Width Timing Errors in Integrated Circuit Testing	65.0307
S. Korea	0045456/2001	7/27/01	Superconducting Single Photon Detector	65.0332
S. Korea	0050697/2001	8/22/01	TIME-TO-DIGITAL CONVERTER	65.0296
S. Korea	51333/2001	8/24/01	EDGE PLACEMENT AND JITTER MEASUREMENT FOR ELECTRONIC ELEMENTS	65.0297
S. Korea	59897/2001	9/27/01	On-Chip Optically Triggered Latch for IC Time Measurements	65.0324
S. Korea	10-2001-0059997	9/27/01	Method and Apparatus for Remotely Testing Semiconductor	65.0340
S. Korea	60418/2001	9/28/01	Compact, High Collection Efficiency Scintillator for Secondary Electron Detection	65.0322
S. Korea	00600419/2001	9/28/01	Method and Apparatus for High Speed IC Test Interface	65.0337
S. Korea	0065625/2001	10/24/01	Scan Stream Sequencing for Testing Integrated Circuits	65.0321

Country	App. No.	App. Date	Title	ID No.
S. Korea	0082422/2001	12/21/01	Optical Coupling for Testing Integrated Circuits	65.0329
S. Korea	0016318/2002	3/26/02	Method and Apparatus for Socket Calibration of Integrated Circuit Testers	65.0352
Singapore	200105909-6	9/26/01	Method and Apparatus for Remotely Testing Semiconductor	65.0340
Taiwan	87101512	2/5/98	DUAL-LASER VOLTAGE PROBING OF IC'S	65.0261
Taiwan	89119176	9/18/00	Double-Pulsed Optical Interferometer for Waveform Probing of Integrated Circuits	65.0316
Taiwan	89120494	12/1/00	Test Method and Apparatus for Source Synchronous Signals	65.0309
Taiwan	90101828	1/31/01	Socket Calibration Method and Apparatus	65.0302
Taiwan	89127898	1/31/01	Differential Pulsed Laser Beam Probing of Integrated Circuits	65.0312
Taiwan	9012312	8/20/01	TIME-TO-DIGITAL CONVERTER	65.0296
Taiwan	90120431	8/20/01	EDGE PLACEMENT AND JITTER MEASUREMENT FOR ELECTRONIC ELEMENTS	65.0297
Taiwan	90117378	9/3/01	Superconducting Single Photon Detector	65.0332
Taiwan	90122395	9/6/01	On-Chip Optically Triggered Latch for IC Time Measurements	65.0324
Taiwan	90124440	10/3/01	Scan Stream Sequencing for Testing Integrated Circuits	65.0321
Taiwan	90123501	10/12/01	Method and Apparatus for High Speed IC Test Interface	65.0337
Taiwan	90130971	12/13/01	Optical Coupling for Testing Integrated Circuits	65.0329
Taiwan	91105007	3/15/02	Method and Apparatus for Socket Calibration of Integrated Circuit Testers	65.0352
Taiwan	091105226	3/19/02	Test System Formatters	65.0348
Taiwan	0911052254	3/19/02	Low-Jitter Clock for Test System	65.0349
Taiwan	091105225	3/19/02	Test System Algorithmic Program Generators	65.0350
Taiwan	091107758	4/16/02	Measuring Back-Side Voltage of an Integrated Circuit	65.0354
Taiwan	091108979	4/30/02	Open-Loop for Waveform Acquisition	65.0355
U.K.	0100780.6	1/11/01	Test Method and Apparatus for Source Synchronous Signals	65.0309
U.K.	01919529.6	3/19/01	Column Simultaneously Focusing a Particle Beam and an Optical Beam	65.0290

## Schedule B

Trademarks:

Country	Trademark	Serial Number	Registration
U.S.	Accelerated Vector Mode	74/655,764	2,198,732
U.S.	Arrow		
U.S.	ASAP	74/295198	1,813,447
U.S.	ASAP	74/083792	1,887,766
U.S.	AutoEdge		
U.S.	AVM	74/655,766	2,099,862
U.S.	BatchProbe	75/195,094	2,307,702
U.S.	BATCHREPAIR	75/195,026 (abandoned)	
U.S.	BATCHREPAIR	76/191,969 (abandoned)	
U.S.	DART		
U.S.	DeFT	76/228570 (abandoned)	
U.S.	DeFT	76/257564 (abandoned)	
U.S.	ETC1000		
U.S.	EXA 3000		
U.S.	EXA2000		
U.S.	GBS		
U.S.	Gigabit Sampler		
U.S.	IDS	74/177,780	1,774,080
U.S.	IDS OptiFIB	76/284,263	
U.S.	IDS5000		
U.S.	Integrated Test Facility (ITF)		
U.S.	InterActiv Services		
U.S.	ISOCHRONOUS FABRIC INTERFACE	78/175,606	
U.S.	ITS	75/298,146	2,252,458
U.S.	JAVELIN		
U.S.	Keep Alive	74/387,205	1,837,767
U.S.	NanoBlade	76/081,008 (abandoned)	
U.S.	NetTracer	75/195,095 (abandoned)	
U.S.	NP Platform	78/244,106	
U.S.	NPTest IDS OptiFIB	78/201,707	
U.S.	NPTest	76/446026	
U.S.	NxGenConnect	76/340933	
U.S.	NxGenSupport	76/340932	
U.S.	ONIDIA		
U.S.	OptiCA	78/201,756	
U.S.	Performer/Performa		
U.S.	PICA		
U.S.	RDRAM		
U.S.	RDX2200		
U.S.	SABER	75/301,652	2,345,915
U.S.	Sapphire		
U.S.	Sapphire NP	78/244,117	
U.S.	SEMIQUEST		
U.S.	Sequencer-Per-Pin	74/083,754	1,759,075
U.S.	Sprint		

Country	Trademark	Serial Number	Reg. No.
U.S.	TESTER PER BOARD		
U.S.	The Eye of the FIB		
U.S.	Through Silicon		
U.S.	TimeStamper	76/333,767	
U.S.	TruEdge		
U.S.	TruSite		
U.S.	XTOS		
Benelux	NanoBlade	0968038	
Benelux	Sequencer-Per-Pin	730605	465805
Canada	ASAP	644,115	
China	NanoBlade	2000118605	
China	NxGenSupport	3242989	
CTM	IDS OptiFIB	002518397	
France	NanoBlade	003037591	003037591
France	Sequencer Per Pin	1542822	1542822
Germany	NanoBlade	300 49 118.2/09	30049118
Germany	Sequencer-Per-Pin		
Italy	Sequencer-Per-Pin	22149C/89	557736
Japan	ASAP	01-073912	2663770
Japan	IDS	134,794/1996	
Japan	IDS OptiFIB	2002-001113	
Japan	RDX 2200		
Japan	SABER	2000-129870	
Japan	SABER	2000-129870	
Japan	Sequencer-Per-Pin	01-073911	2670975
Japan	TruEdge		
S. Korea	ASAP		
S. Korea	IDS OptiFIB	40-2001-57497	
S. Korea	RDX 2200		
S. Korea	Sequencer-Per-Pin	89-16290	210717
Singapore	ASAP	4706/1989	4706/89
Singapore	NanoBlade	T00/12054Z	
Singapore	Sequencer-Per-Pin	4645/89	4646/1989
Taiwan	ASAP	78/30190	502574
Taiwan	RDX 2200		
Taiwan	Sequencer-Per-Pin	78/030189	502573
U.K.	Sequencer-Per-Pin	1388155	1388155

## GENERAL ASSIGNMENT AND ASSUMPTION AGREEMENT

This General Assignment and Assumption Agreement (this "Agreement"), dated as of May 10, 2002, by and between Schlumberger Technologies, Inc., a Delaware Corporation ("STI" or the "Assignor"), and Schlumberger Technology Solutions LLC, a Delaware limited liability company ("STS LLC" or the "Assignee").

### WITNESSETH

**WHEREAS**, Assignor desires to transfer certain of its assets to Assignee in consideration of, among other things, Assignee's assumption of certain liabilities of Assignor, and the issuance of interests in Assignee; and

**WHEREAS**, Assignee desires to accept that transfer of certain assets and liabilities from Assignor;

**NOW, THEREFORE**, for and in consideration of the agreements contained herein and other good and valuable consideration, the receipt and sufficiency of which are hereby acknowledged, the parties hereby agree as follows:

1. Assignor does hereby grant, sell, convey, assign and deliver all of the assets described on Schedule 1 hereto (collectively, the "Conveyed Assets"), unto Assignee, and Assignee's successors and assigns on an "as is," "where is" basis, and Assignee hereby accepts and assumes from Assignor, the assets, properties and rights hereby granted, sold, conveyed, assigned and delivered.

2. Assignee does hereby assume all Liabilities of Assignor arising out of or related to the Conveyed Assets or arising out of or related to the business and operations transacted with the Conveyed Assets whether incurred or occurring before, on or after the date of this Agreement, including, without limitation, those Liabilities listed on Schedule 2 hereto (collectively, the "Assumed Liabilities") and agrees to pay, discharge or perform those Liabilities when due.

3. Assignor hereby covenants and agrees to and with Assignee, and Assignee's successors and assigns, to execute, acknowledge, and deliver all and every such further conveyance and other instrument and to do such further acts as may be deemed by Assignee to be reasonably necessary or appropriate more fully to assure Assignee and Assignee's successors and assigns that all the Conveyed Assets have been validly conveyed hereby, or to aid and assist in collecting and reducing to possession, any of or all of the Conveyed Assets, or in connection with the settlement of any obligations or liabilities to Assignor.

4. Assignee hereby covenants and agrees to and with Assignor and Assignor's successors and assigns, to execute, acknowledge, and deliver all and every such further conveyance and other instrument and to do such further acts as may be deemed by Assignor to be reasonably necessary or appropriate more fully to assure Assignor and Assignor's successors and assigns that all the Assumed Liabilities have been validly conveyed hereby.

5. (a) If there are prohibitions against, or conditions to, the conveyance of any of the Conveyed Assets or the assumption of any of the Assumed Liabilities without the prior written consent of third parties, including governmental authorities, whose consent is needed for the transfer of any of the Conveyed Assets or the assumption of any of the Assumed Liabilities or

the issuance of any necessary licenses, permits or other authorizations, which if not satisfied would result in a breach of such prohibitions or conditions or would give an outside party the right to terminate or limit any right of the Assignee with respect to any Conveyed Asset or Assumed Liability or allow the outside party to receive a payment or other consideration then any provisions contained in this Agreement to the contrary notwithstanding, the transfer of title to, or interest in, such Conveyed Asset, or the assumption of such Assumed Liability pursuant to this Agreement shall not become effective unless and until such restrictions on transfer are satisfied, waived or no longer applies.

(b) The parties shall cooperate to effect such transfers as promptly as shall be practicable. Nothing herein shall be deemed to require the transfer of any Conveyed Assets or the assumption of any Assumed Liabilities that by their terms or operation of law cannot be transferred or assumed; provided, however, that the parties shall cooperate to obtain any necessary consents or approvals for the transfer of all Conveyed Assets and the assumption of all Assumed Liabilities contemplated to be transferred or assumed pursuant to this Agreement and shall, even in the absence of any necessary consents or approvals, transfer the equitable ownership of Assets when such a transfer is permitted. In the event that any such transfer of Conveyed Assets or assumption of Assumed Liabilities is not consummated as of the date of this Agreement the party retaining such Conveyed Asset or Assumed Liability shall thereafter hold such Conveyed Asset in trust for the use and benefit of the party entitled thereto (at the expense of the party entitled thereto) and retain such Assumed Liability for the account of the party by whom such Assumed Liability is to be assumed, pursuant hereto, and take such other action as may be reasonably requested by the party to which such Conveyed Asset is to be transferred, or by whom such Assumed Liability is to be assumed, as the case may be, in order to place such party, insofar as reasonably possible, in the same position as would have existed had such Conveyed Asset or Assumed Liability been transferred or assumed as contemplated hereby. As and when any such Conveyed Asset becomes transferable or such Assumed Liability can be assumed, such transfer or assumption shall be effected forthwith. Subject to the foregoing, the parties agree that, as of the date of this Agreement, each party hereto shall be deemed to have acquired complete and sole beneficial ownership over all of the Conveyed Assets, together with all rights, powers and privileges incident thereto, and shall be deemed to have assumed in accordance with the terms of this Agreement all of the Assumed Liabilities, and all duties, obligations and responsibilities incident thereto, which such party is entitled to acquire or required to assume pursuant to the terms of this Agreement.

(c) If after two years from the date of this Agreement any Conveyed Asset remains subject to an arrangement described in Section 5(b) unless the parties elect to continue such arrangement on such terms as they may mutually agree, such arrangement shall terminate. In the event of a termination, the beneficial owner may (i) direct the party acting as trustee to transfer the Conveyed Asset to the beneficial owner, at the sole risk of such owner (which will thereafter indemnify the trustee/transferor from all losses, claims, damages, Liabilities, lawsuits, actions, costs and expenses, including reasonable attorneys' fees, arising as a result of such transfer), (ii) direct the party acting as trustee to sell or liquidate the subject Conveyed Asset for the account of, and at the sole risk and expense of, such owner, which shall be entitled to receive all of the net proceeds of such sale or liquidation or (iii) direct the party acting as trustee to purchase the affected Conveyed Asset at a price mutually agreed or, if no such agreement is reached, at the fair market value thereof as determined by a neutral third-party appraisal process.

This Agreement shall be governed by and construed in accordance with the laws of the State of Delaware, without regard to the conflicts of laws provisions thereof.

IN WITNESS WHEREOF, the parties have caused this Agreement to be duly executed as of the date first set forth above.

ASSIGNOR:

SCHLUMBERGER TECHNOLOGIES INC.

By: 

Name: Jurren Schoonbeek  
Title: Vice President

ASSIGNEE:

SCHLUMBERGER TECHNOLOGY SOLUTIONS LLC

By: \_\_\_\_\_

Name:  
Title:



IN WITNESS WHEREOF, the parties have caused this Agreement to be duly executed as of the date first set forth above.

**ASSIGNOR:**

**SCHLUMBERGER TECHNOLOGIES, INC.**

By: \_\_\_\_\_

Name:

Title:

**ASSIGNEE:**

**SCHLUMBERGER TECHNOLOGY SOLUTIONS LLC**

By: Ashik Belani

Name:

Title:

## SCHEDULE 1

to the

### General Assignment and Assumption Agreement

The following Conveyed Assets shall be transferred by Assignor to Assignee:

All of the assets of the Semiconductor Solutions Group related to the Test, Probe and SABER business segments ("Test, Probe and SABER") of Assignor (i) represented on the Balance Sheet, dated as of March 31, 2002, attached herewith as Exhibit A (the "Balance Sheet"), (ii) written off, expensed or fully depreciated that, had they not been written off, expensed or fully depreciated, would have been reflected in the Balance sheet in accordance with the principles and accounting policies under which the Balance Sheet was prepared; and (iii) acquired after the date of the Balance Sheet that would be reflected in the Balance Sheet if such Balance Sheet were prepared, including any business transaction processing that may occur on the systems of Assignor or its affiliates during the period from the date of the Balance Sheet through the date of separation, including in the case of (i) through (iii) above, without limitation, all of the:

- (a) real property, leaseholds and subleaseholds therein, improvements, fixtures, and fittings thereon, and easements, rights-of-way, and other appurtenants thereto;
- (b) tangible personal property (such as machinery, equipment, inventories of raw materials and supplies, manufactured and purchased parts, goods in process and finished goods, furniture, automobiles, trucks, tractors, trailers, tools, jigs, and dies);
- (c) intellectual property, goodwill associated therewith, licenses and sublicenses granted and obtained with respect thereto, and rights thereunder, remedies against infringements thereof, and rights to protection of interests therein under the laws of all jurisdictions;
- (d) agreements, contracts, indentures, mortgages, instruments, security interests, guaranties, other similar arrangements, and rights thereunder, including but not limited to the following contracts:
  - Intel Corporation Purchase Agreement, between Intel Corporation, as Buyer, and Schlumberger Technologies ATE Division, as Seller; and
  - PICA Tooling Technology License and Joint Development Agreement, between International Business Machines Corporation and Schlumberger Technologies, Inc.;
- (e) accounts, notes, and other receivables;
- (f) claims, deposits, prepayments, refunds, causes of action, chooses in action, rights of
- (g) recovery, rights of set off, and rights of recoupment, but excluding any such item relating to the payment of taxes;
- (h) franchises, approvals, permits, licenses, orders, registrations, certificates, variances, and similar rights obtained from governments and governmental agencies;
- (i) books, records, ledgers, files, documents, correspondence, lists, plats, architectural plans;
- (j) drawings, and specifications, creative materials, and advertising and promotional materials;
- (k) studies, reports, and other printed or written materials, and rights in and with respect to the assets associated with its employee benefit plans;

provided, however, that the Conveyed Assets shall not include (i) any assets required or used by the Assignor in relation to any business of the Assignor other than Test, Probe and

SABER, unless such assets are expressly allocated to Test, Probe and SABER pursuant to the books and records of Assignor, and (ii) any of the rights of the Assignor under this Agreement.

End of Schedule

## SCHEDULE 2

to the

### General Assignment and Assumption Agreement

The following Assumed Liabilities shall be assumed by Assignee from Assignor:

All of the liabilities, obligations, claims and commitments (whether known or unknown, whether asserted or unasserted, whether absolute or contingent, whether accrued or unaccrued, whether liquidated or unliquidated, and whether due or to become due) of the Semiconductor Solutions Group related to the Test, Probe and SABER business segments ("Test, Probe and SABER") of Assignor, whether or not the same would be required by generally accepted principles and accounting policies to be reflected in financial statements or disclosed in the notes thereto, including, without limitation:

- (a) all liabilities and obligations of Test, Probe & SABER of Assignor represented on the Balance Sheet, subject to any discharge subsequent to the date of the Balance Sheet;
- (b) all liabilities and obligations of Test, Probe & SABER of Assignor arising after the date of the Balance Sheet that would be reflected in the Balance Sheet if the Balance Sheet were prepared using the same principals and accounting policies under which the Balance Sheet was prepared;
- (c) all liabilities and obligations of Test, Probe & SABER of Assignor under the agreements, contracts, leases, licenses, and other arrangements referred to in relation to the Conveyed Assets;
- (d) all liabilities and obligations of Test, Probe & SABER under existing Assignor employee benefit plans;
- (e) all obligations of Test, Probe & SABER of Assignor to indemnify any person by reason of the fact that he or it was an employee or agent of Test, Probe & SABER or was serving at the request of Test, Probe & SABER as an employee, or agent of another entity (whether such indemnification is for judgments, damages, penalties, fines, costs, amounts paid in settlement, losses, expenses, or otherwise and whether such indemnification is pursuant to any statute, agreement, or otherwise); and
- (f) all other liabilities and obligations of Test, Probe & SABER of Assignor;

provided, however, that the Assumed Liabilities shall not include (i) any liability or obligation under the existing Assignor employee benefit plans relating to pensions and retiree medical benefits, including, without limitations the Schlumberger Technology Corporation Pension Plan, Schlumberger Group Health Care Plan and Schlumberger Technologies Inc. Savings and Profit Sharing Plan, (ii) any liability or obligation arising from any proceeding or suit which is pending against Assignor or the Test, Probe and SABER business segments of Assignor as of the date hereof, and (iii) any cost or expense incurred by Test, Probe & SABER required for the consummation of the transactions contemplated in this Agreement.

End of Schedule